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Will	6,28	1,532 B1	8/28/2001		Doyle et al.		<u> </u>	_ _			1
WLL	5,6	583,934	11/4/97		Candelaria						
WILL	6,36	8,931 B1	4/9/2002		Kuhn, et al.	<u>.                                     </u>	1			٠.	
WILL	5,3	10,446	5/10/94		Konishi et al.						
wil	4,8	353,076	8/1/89		Tsaur et al.						
WU	US 2002	/0090791 A1	7/11/2002		Doyle et al.		T			-	7"
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CNL	6.50	9,618 B2	1/21/2003		Jan et al.						
W		6,462 B2	11/5/2002		Shimizu et al.						
W		2,082 B1	3/26/2002		Doyle et al.	1				-	
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SILI		/0040158 <b>′</b> A1	2/27/2003		Saitoh			1			
2747		/0086472 <b>\</b> A1	7/4/2002		Roberds et al.		1			1.	
2141		1,964 B1	2/18/2003		Jan et al.	•   •					· ·
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FEB # 5 2005 FORM PTO-1449 (Modified) ATTY, DOCKET NO. SERIAL NO. 10/707,018 FIS920030189US1 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT: APPLICANT'S INFORMATION DISCLOSURES Doris, et al. STATEMENT (Use several sheets if necessary) FILING DATE: **GROUP:** 11/14/03 REFERENCE DESIGNATION **U.S. PATENT DOCUMENTS EXAMINER** DOCUMENT FILING DATE INITIALS NUMBER DATE NAME CLASS SUBCLASS (IF APPRO.) 5,081,513 1/14/1992 Jackson, et al. 3,602,841 8/31/1971 McGroddy المالك. Bosco, et al. 3/11/2003 6,531,740 3/11/2003 6,531,369 Ozkan, et al. 12/31/2002 6,501,121 Yu, et al. 6,498,358 12/24/2002 Lach, et al. 12/10/2002 Ramdani, et al. 6,493,497 6/11/2002 Brunner, et al. 6,403,975 6,361,885 3/26/2002 Chou 6,255,169 7/3/2001 Li, et al. 6/12/2001 Brady, et al. 6,246,095 6,165,383 12/26/2000 Chou 6,133,071 10/17/2000 Nagai 4/4/2000 Schetzina 6,046,464 6,025,280 2/15/2000 Brady, et al. FOREIGN PATENT DOCUMENTS DOCUMENT' TRANSLATION SUBCLASS NUMBER DATE COUNTRY **CLASS** YES NO OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.) DATE CONSIDERED **EXAMINER** 

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WU	5,880,040	3/9/1999	Sun, et al.		1 1			<del>                                     </del>
WLL	5,861,651	1/19/1999	Brasen, et al.	<del>                                     </del>	<del></del>			+
(NL	5,679,965	10/21/1997	Schetzina	1		-		<del> </del>
TULL	5,670,798	9/23/1997	Schetzina				<del></del>	+
WL	5,561,302	10/1/1996	Candelaria		+			+
WLL	5,471,948	12/5/1995	Burroughes, et al.	1		$\dashv$	<del>~</del>	+
WLL	5,459,346	10/17/1995	Asakawa, et al.					<del> </del>
WU	5,391,510	2/21/1995	Hsu, et al.	-	1	$\dashv$		+
bil	5,371,399	12/6/1994	Burroughes, et al.	1	1 1	$\neg$	<del></del>	+
LILL	5,108,843	4/28/1992	Ohtaka, et al.					1
LAU!	5,060,030	10/22/1991	Hoke	1			<del> </del>	†
We	4,958,213	9/18/1990	Eklund, et al.		<del></del>			†—
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WU	6,284,626	9/4/2001	Kim						
WU	6,274,444	8/14/2001	Wang						
WLU	6,261,964	7/17/2001	Wu, et al.				<b>†</b>		
WW	6,221,735	4/24/2001	Manley, et al.						
WW	6,117,722	9/12/2000	Wuu, et al.			1			
ww	6,107,143	8/22/2000	Park, et al.						
Wi	6,090,684	7/18/2000	Ishitsuka, et al.						
MU	6,066,545	5/23/2000	Doshi, et al.						
ill	6,008,126	12/28/1999	Leedy			1 1	***************************************		
W	5,946,559	8/31/1999	Leedy						
W	5,840,593	11/24/1998	Leedy						
للالا	5,592,018	1/7/1997	Leedy						
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me	5,571,741	11/5/1996	Leedy	V					
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WLC	5,557,122	9/17/1996	Shrivastava, et al.			$\overline{I}$		(	j		
WL	5,354,695	10/11/1994		Leedy		1					
WU	5,134,085	7/28/1992		Gilgen, et al.							
VIL	5,006,913	4/9/1991		Sugahara, et al.			1				
INLL	4,952,524	8/28/1990		Lee, et al.							
WIL	4,855,245	8/8/1989		Neppl, et al.	7						
WL	2002/0086497	07-04-2002	·	Kwok	17						
MU	5,960,297	09-28-1999		Saki	17						
M	6,403,486	06-11-2002		Lou	TT						
WU	6,284,623	09-04-2001		Zhang et al.	$\Pi$						
We	2003/0032261	02-13-2003		Yeh et al.						-	
المال	2003/0057184	03-27-2003		Yu et al.				7			
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الما	2003/0067035	04-10-2003		Tews et al.	$\Pi$				7	· · · · · · · · · · · · · · · · · · ·	
Uhl	6,461,936	10-08-2002	,	on Ehrenwall				1			
/NL	6,319,794	11-20-2001		Akatsu et al.	IT						
we.	2001/0009784	07-26-2001		Ma et al.		************	i				
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WL	2002 Symposium	On VLSI Tech	nology	evice Design of Sub-1 Digest of Technical P	apers, IEE	E, pp 98-99.	1
NU	Gregory Scott, et Isolation Induced	al., "NMOS Dri Stress", Interna	ive Cun ational	rent Reduction Cause Electron Devices Mee	d by Transi ting, 34.4.1	stor Layout and , IEEE, Septem	Trench hber 1999.
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WA		G. Zhang, J. Cressler, C SiGe Bipolar Transistor	G. Niu, A. Joseph, rs <sup>n</sup> . IEEE Transa	"A New 'I ctions on I	Mixed-Mode' Reliability Electron Devices, vol. 49	Degradation 1, no. 12, Decem	Viechanism in A aber 2002, pp. 2	dvanced Si and 2151-56.
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